

## ABSTRACT

A test probe apparatus having a housing and a probe pin is provided. The housing includes a first housing end portion having a round tapered wall defining a tapered cavity. The probe pin includes a pin base portion rigidly mounted to the housing and a pin tip portion movably mounted to the housing for movement between a first position and a second position. At the first position, the pin tip portion is disposed in a spaced-apart relationship with the pin base portion and protrudes into the tapered cavity. At the second position, the pin tip portion is moved toward the pin base portion relative to the first position.